Abstract **Document Sections** I. Introduction

Characterization of an Integrated Fluorescence-Detection Hybrid Device With Photodiode and Organic Light-Emitting Diode **IEEE Electron Device Letters** Published: 2006

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Abstract:

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III. Turbidity

This paper presents a flexible turbidity sensing system that implements single and multiple infrared (IR) beam architectures. The hardware includes two pairs of IR LED -IR photodiode whose relative position permits the materialization of different architectures for turbidity optical measurement. The control of the sensing architecture is performed by a microcontroller based I/O board that is wireless connected to a PC for advanced control and data processing based on neural networks. Using intelligent processing procedures, the best turbidity measurement architecture is selected in terms of measurement accuracy for a given turbidity level. Elements of neural network design, optimization and embedding as part of an advanced processing software component

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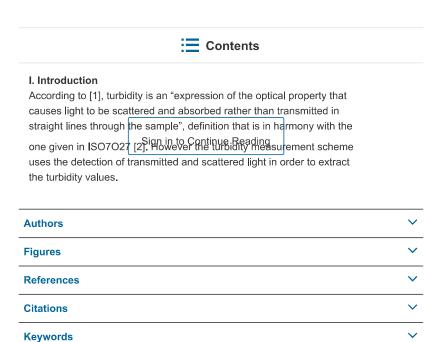
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